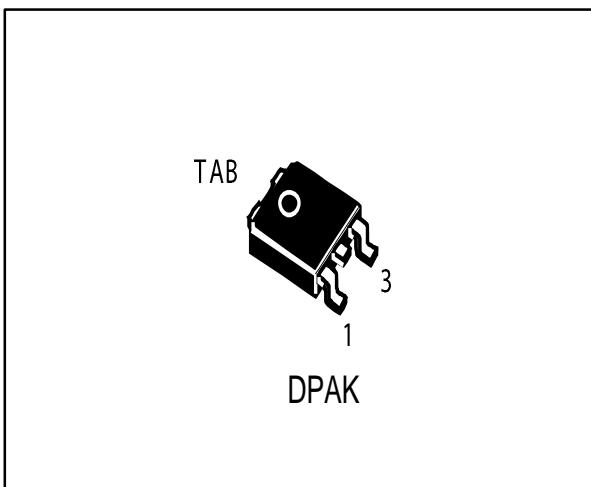
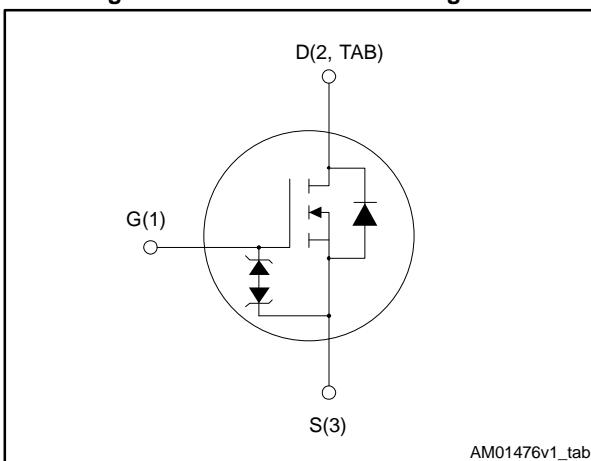


## N-channel 600 V, 0.340 $\Omega$ typ., 11 A MDmesh™ M2 EP Power MOSFET in a DPAK package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STD15N60M2-EP	650 V	0.378 $\Omega$	11 A

- Extremely low gate charge
- Excellent output capacitance (C<sub>oss</sub>) profile
- Very low turn-off switching losses
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications
- Tailored for very high frequency converters (f > 150 kHz)

### Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 EP enhanced performance technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance, optimized switching characteristics with very low turn-off switching losses, rendering it suitable for the most demanding very high frequency converters.

**Table 1: Device summary**

Order code	Marking	Package	Packaging
STD15N60M2-EP	15N60M2EP	DPAK	Tube

## Contents

<b>1</b>	<b>Electrical ratings .....</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics .....</b>	<b>4</b>
2.1	Electrical characteristics (curves) .....	6
<b>3</b>	<b>Test circuits .....</b>	<b>8</b>
<b>4</b>	<b>Package mechanical data .....</b>	<b>10</b>
4.1	DPAK (TO-252) type A.....	11
<b>5</b>	<b>Revision history .....</b>	<b>14</b>

# 1 Electrical ratings

**Table 2: Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	11	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	7	A
$I_{DM}^{(1)}$	Drain current (pulsed)	44	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	110	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature		

**Notes:**

(1) Pulse width limited by safe operating area.

(2)  $I_{SD} \leq 11$  A,  $dI/dt \leq 400$  A/ $\mu\text{s}$ ;  $V_{DS}$  peak <  $V_{(BR)DSS}$ ,  $V_{DD} = 400$  V.(3)  $V_{DS} \leq 480$  V**Table 3: Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	1.14	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max	50	$^\circ\text{C}/\text{W}$

**Notes:**(1) When mounted on FR-4 board of 1 inch<sup>2</sup>, 2 oz Cu**Table 4: Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	2.8	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ ; $V_{DD} = 50$ V)	125	mJ

## 2 Electrical characteristics

$T_c = 25^\circ\text{C}$  unless otherwise specified

Table 5: On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
$I_{\text{DSS}}$	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}, T_c = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 5.5 \text{ A}$		0.340	0.378	$\Omega$

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	590	-	pF
$C_{oss}$	Output capacitance		-	30	-	pF
$C_{rss}$	Reverse transfer capacitance		-	1.1	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	148	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	7	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 11 \text{ A}, V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 15: "Gate charge test circuit"</a> )	-	17	-	nC
$Q_{gs}$	Gate-source charge		-	3.1	-	nC
$Q_{gd}$	Gate-drain charge		-	7.3	-	nC

**Notes:**

<sup>(1)</sup> $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

Table 7: Switching energy

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$E_{(\text{off})}$	Turn-off energy (from 90% $V_{GS}$ to 0% $I_D$ )	$V_{DD} = 400 \text{ V}, I_D = 1.5 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	4.7	-	$\mu\text{J}$
		$V_{DD} = 400 \text{ V}, I_D = 3.5 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$	-	5.2	-	$\mu\text{J}$

Table 8: Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}$ , $I_D = 5.5 \text{ A}$ $R_G = 4.7 \Omega$ , $V_{GS} = 10 \text{ V}$ (see <a href="#">Figure 14: "Switching times test circuit for resistive load"</a> and <a href="#">Figure 19: "Switching time waveform"</a> )	-	11	-	ns
$t_r$	Rise time		-	10	-	ns
$t_{d(off)}$	Turn-off-delay time		-	40	-	ns
$t_f$	Fall time		-	15	-	ns

Table 9: Source drain diode

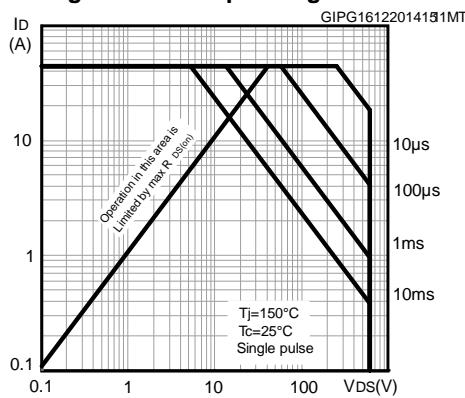
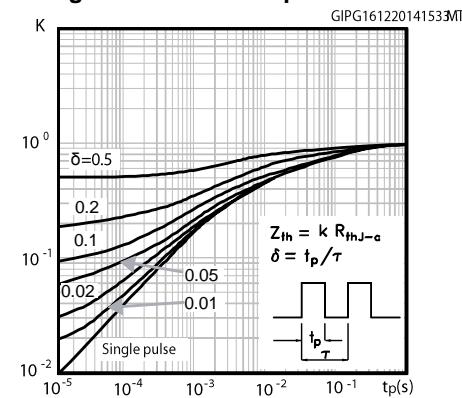
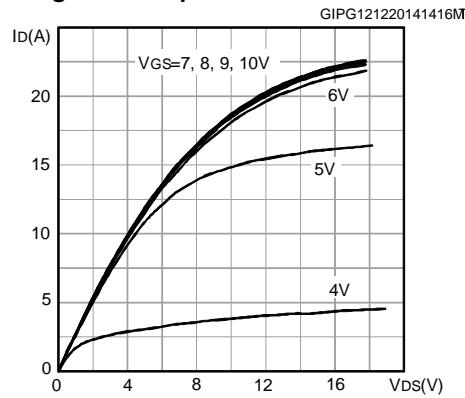
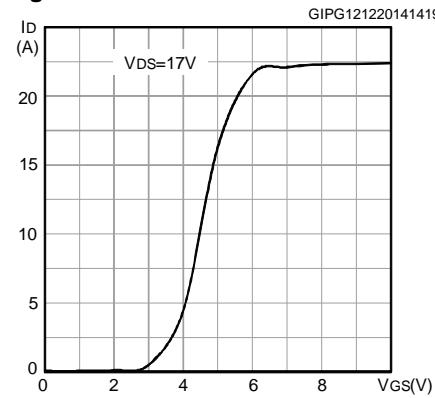
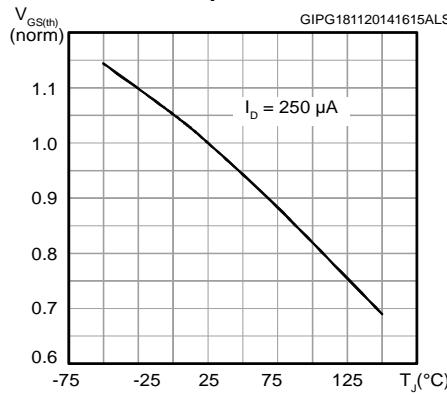
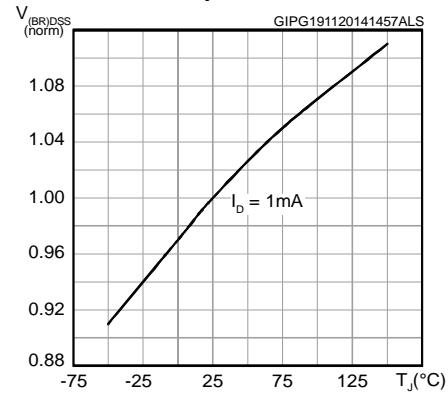
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		11	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		44	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$ , $I_{SD} = 11 \text{ A}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 11 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ (see <a href="#">Figure 16: "Test circuit for inductive load switching and diode recovery times"</a> )	-	280		ns
$Q_{rr}$	Reverse recovery charge		-	2.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	19.5		A
$t_{rr}$	Reverse recovery time		-	400		ns
$Q_{rr}$	Reverse recovery charge	$I_{SD} = 11 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ , $T_j = 150^\circ\text{C}$ (see <a href="#">Figure 16: "Test circuit for inductive load switching and diode recovery times"</a> )	-	3.8		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	19		A

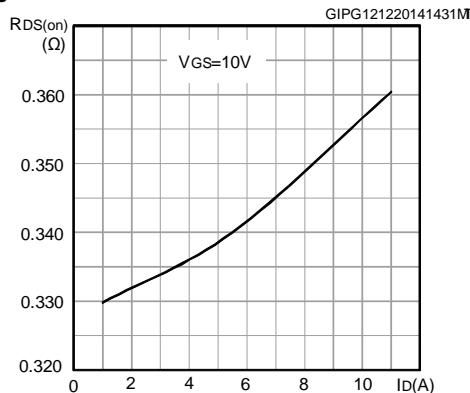
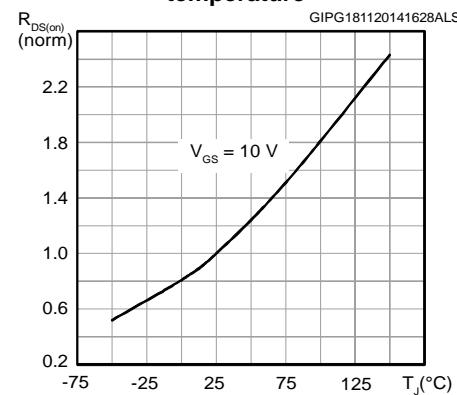
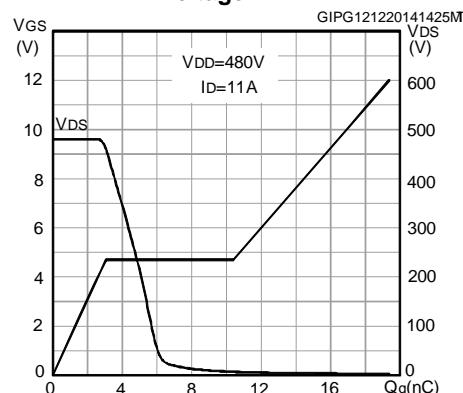
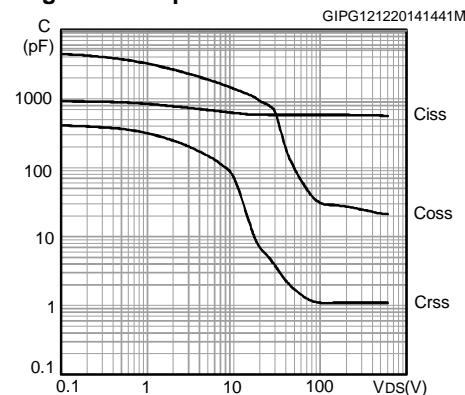
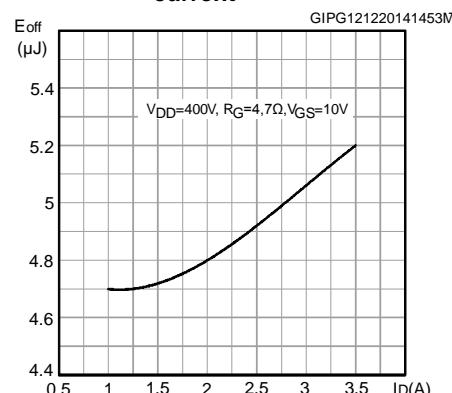
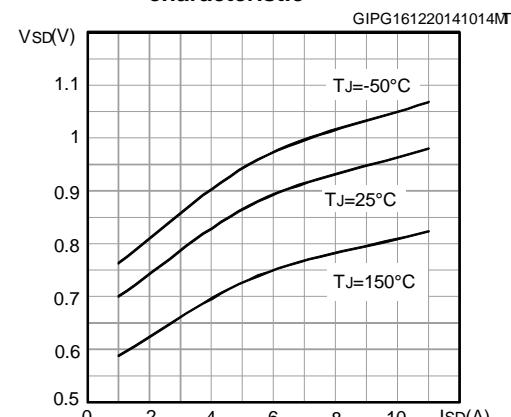
**Notes:**

(1)Pulse width is limited by safe operating area

(2)Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

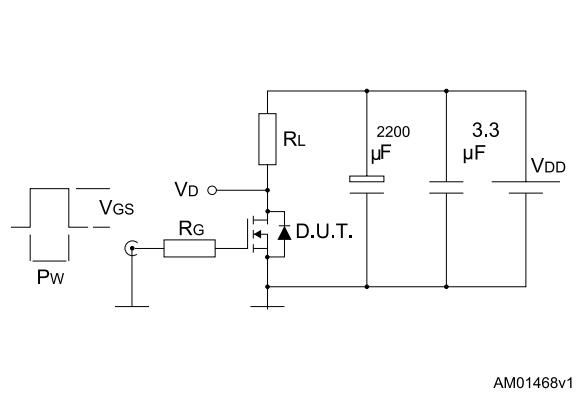
## 2.2 Electrical characteristics (curves)

**Figure 2: Safe operating area****Figure 3: Thermal impedance****Figure 4: Output characteristics****Figure 5: Transfer characteristics****Figure 6: Normalized gate threshold voltage vs temperature****Figure 7: Normalized V(BR)DSS vs. temperature**

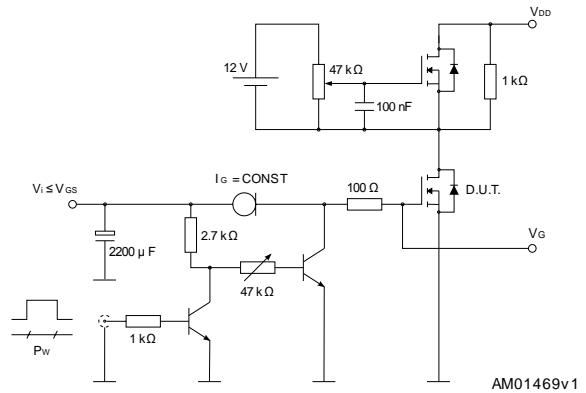
**Figure 8: Static drain-source on-resistance****Figure 9: Normalized on-resistance vs temperature****Figure 10: Gate charge vs. gate-source voltage****Figure 11: Capacitance variations****Figure 12: Turn-off switching loss vs drain current****Figure 13: Source-drain diode forward characteristic**

### 3 Test circuits

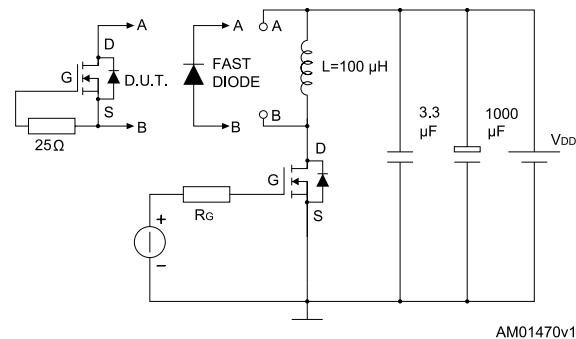
**Figure 14: Switching times test circuit for resistive load**



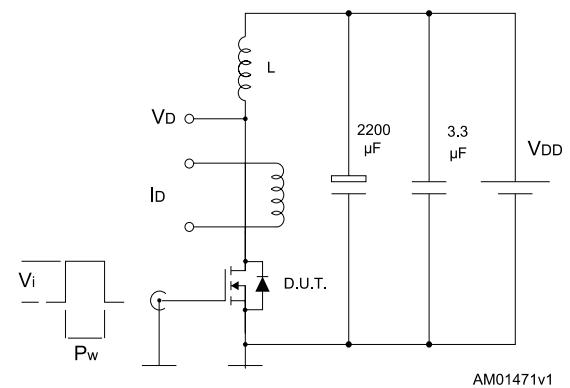
**Figure 15: Gate charge test circuit**

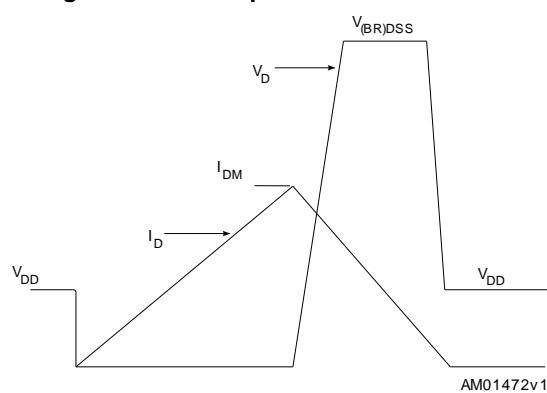
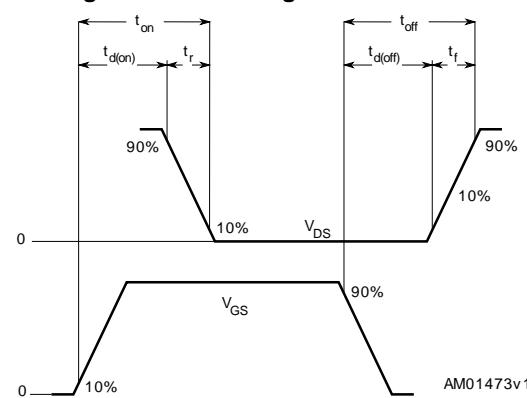


**Figure 16: Test circuit for inductive load switching and diode recovery times**



**Figure 17: Unclamped inductive load test circuit**



**Figure 18: Unclamped inductive waveform****Figure 19: Switching time waveform**

## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

## 4.1 DPAK (TO-252) type A

Figure 20: DPAK (TO-252) type A package outline

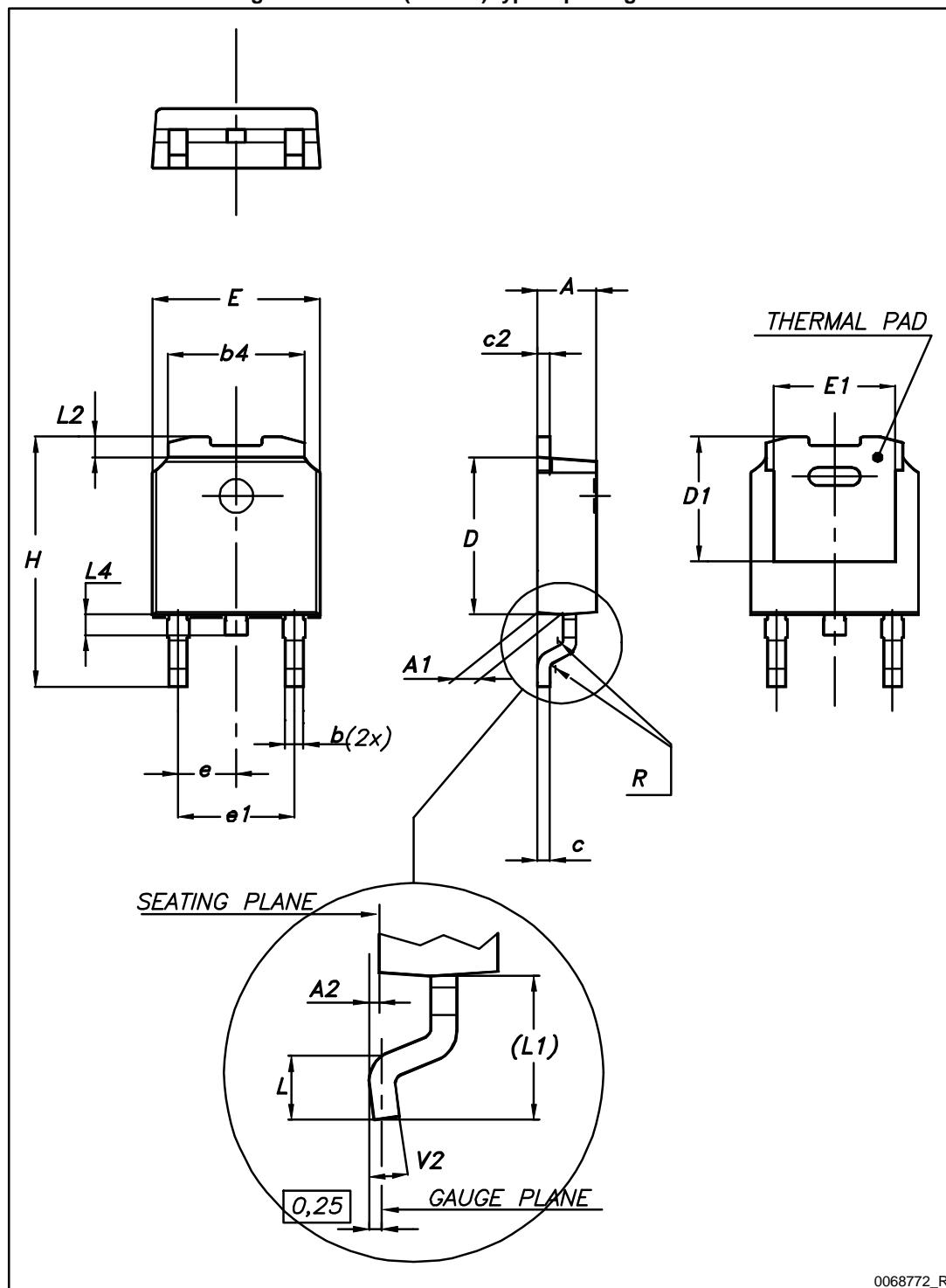
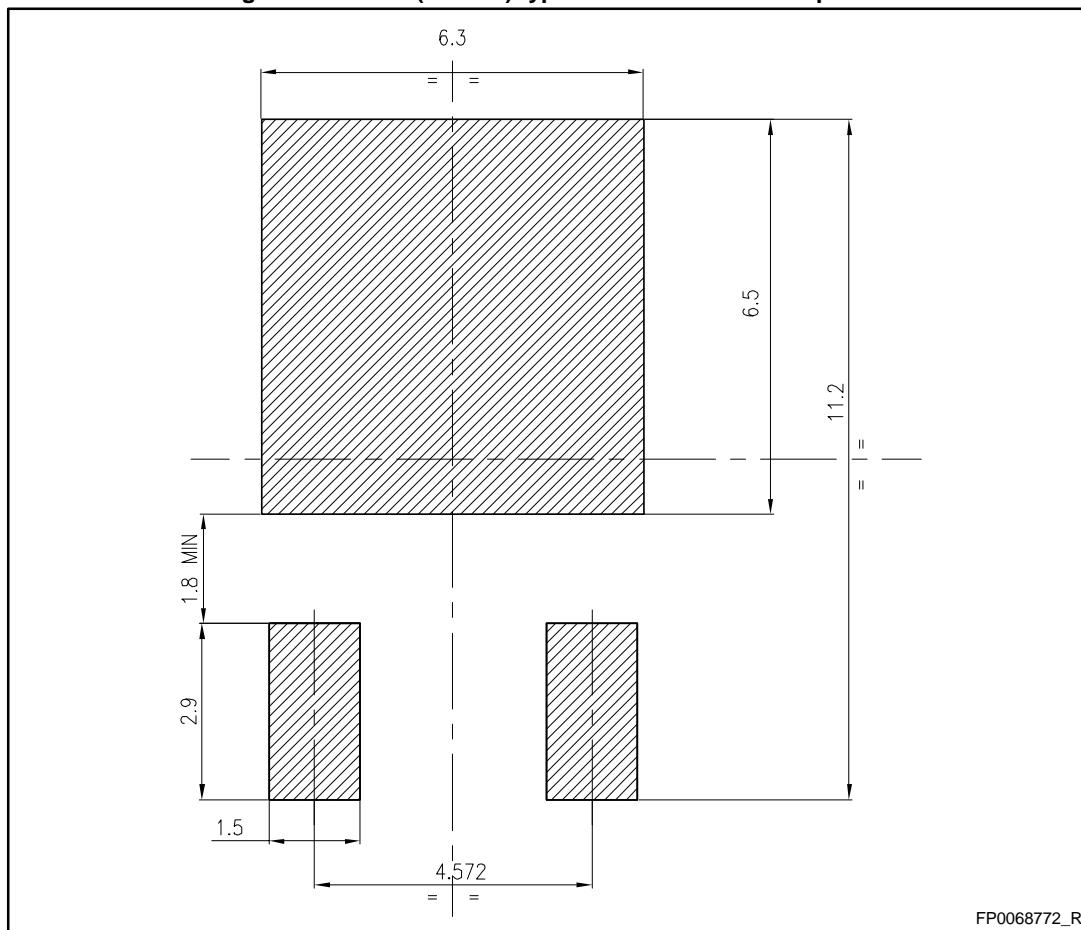


Table 10: DPAK (TO-252) type A mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
e		2.28	
e1	4.40		4.60
H	9.35		10.10
L	1.00		1.50
L1		2.80	
L2		0.80	
L4	0.60		1.00
R		0.20	
V2	0°		8°

Figure 21: DPAK (TO-252) type A recommended footprint



All dimensions are in mm

## 5 Revision history

Table 11: Document revision history

Date	Revision	Changes
16-Dec-2014	1	First release.

**IMPORTANT NOTICE – PLEASE READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2014 STMicroelectronics – All rights reserved